**Product data sheet** 

## 1. General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

#### 2. Features and benefits

- · Low conduction losses due to low on-state resistance
- Q101 compliant
- Suitable for logic level gate drive sources

## 3. Applications

- 12 V and 24 V loads
- Automotive and general purpose power switching
- Motors, lamps and solenoids

### 4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 150 °C		-	-	55	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 5 V; T <sub>sp</sub> = 25 °C; <u>Fig. 3</u> ; <u>Fig. 2</u>		-	-	7	Α
P <sub>tot</sub>	total power dissipation	T <sub>sp</sub> = 25 °C; <u>Fig. 1</u>		-	-	8	W
Static charact	Static characteristics						
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 8 A; T <sub>j</sub> = 25 °C		-	62	73	mΩ
		V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 8 A; T <sub>j</sub> = 25 °C		-	-	89	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 8 \text{ A}; T_j = 25 ^{\circ}\text{C}; Fig. 13;$ Fig. 14		-	68	80	mΩ
Avalanche rug	Avalanche ruggedness						
E <sub>DS(AL)S</sub>	non-repetitive drain- source avalanche energy	$I_D$ = 6 A; $V_{sup} \le 55$ V; $R_{GS}$ = 50 Ω; $V_{GS}$ = 5 V; $T_{j(init)}$ = 25 °C; unclamped		-	-	36	mJ





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## 5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	4	D I
2	D	drain		
3	S	source		G T T
4	D	drain	⊟1 ⊟2 ⊟3 SC-73 (SOT223)	mbb076 S

## 6. Ordering information

Table 3. Ordering information

Type number	Package				
	Name	Description	Version		
BUK9880-55A	SC-73	plastic surface-mounted package with increased heatsink; 4 leads	SOT223		
BUK9880-55A/CU	SC-73	plastic surface-mounted package with increased heatsink; 4 leads	SOT223		

# 7. Marking

Table 4. Marking codes

Type number	Marking code
BUK9880-55A	988055A
BUK9880-55A/CU	988055

# 8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 150 °C	-	55	V
$V_{DGR}$	drain-gate voltage	$R_{GS}$ = 20 k $\Omega$	-	55	V
$V_{GS}$	gate-source voltage		-15	15	V
P <sub>tot</sub>	total power dissipation	T <sub>sp</sub> = 25 °C; <u>Fig. 1</u>	-	8	W
I <sub>D</sub>	drain current	T <sub>sp</sub> = 100 °C; V <sub>GS</sub> = 5 V; <u>Fig. 2</u>	-	4	Α
		T <sub>sp</sub> = 25 °C; V <sub>GS</sub> = 5 V; <u>Fig. 3</u> ; <u>Fig. 2</u>	-	7	Α
I <sub>DM</sub>	peak drain current	$T_{sp}$ = 25 °C; pulsed; $t_p \le 10 \mu s$ ; Fig. 3	-	30	Α

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Symbol	Parameter	Conditions		Min	Max	Unit
T <sub>stg</sub>	storage temperature			-55	150	°C
Tj	junction temperature			-55	150	°C
$V_{GSM}$	peak gate-source voltage	pulsed; t <sub>p</sub> ≤ 50 μs		-15	15	V
Source-dra	in diode					
I <sub>S</sub>	source current	T <sub>sp</sub> = 25 °C		-	7	Α
I <sub>SM</sub>	peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{sp} = 25 \ ^{\circ}C$		-	30	Α
Avalanche	ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D$ = 6 A; $V_{sup} \le 55$ V; $R_{GS}$ = 50 Ω; $V_{GS}$ = 5 V; $T_{j(init)}$ = 25 °C; unclamped		-	36	mJ
E <sub>DS(AL)R</sub>	repetitive drain-source avalanche energy	Fig. 4	[1][2][3]	[ <del>4]</del>	-	J

- [1] Maximum value not quoted. Repetitive rating defined in avalanche rating figure.
- [2] Single-pulse avalanche rating limited by maximum junction temperature of 150 °C.
- [3] Repetitive avalanche rating limited by an average junction temperature of 145 °C.
- [4] Refer to application note AN10273 for further information.

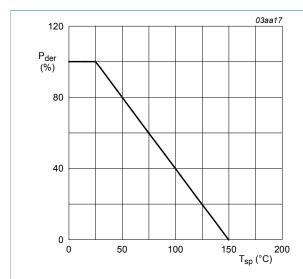


Fig. 1. Normalized total power dissipation as a function of solder point temperature

$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

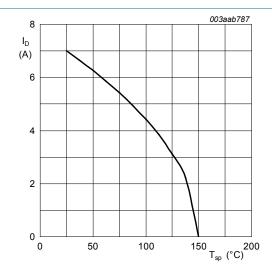


Fig. 2. Continuous drain current as a function of solder point temperature

$$V_{GS} \ge 5V$$

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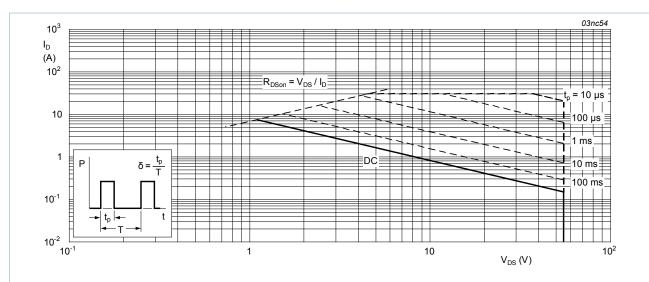


Fig. 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

$$T_{amb} = 25^{\circ}C; I_{DM}$$
 is single pulse

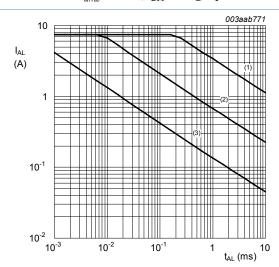


Fig. 4. Single-pulse and repetitive avalanche rating; avalanche current as a function of avalanche time.

- (1) Single-pulse;  $T_j = 25 \, {}^{\circ}C$ .
- (2) Single-pulse;  $T_j = 125 \, ^{\circ}C$ .
  - (3) Repetitive.

### 9. Thermal characteristics

Table 6. Thermal characteristics

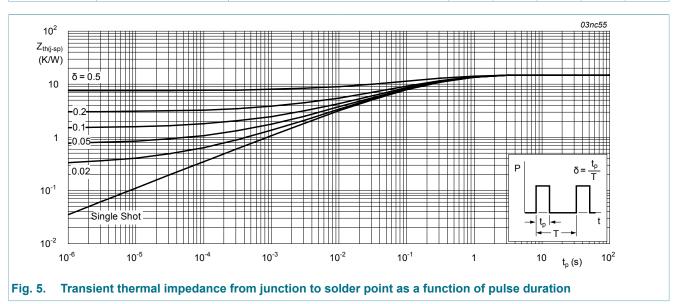
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-sp)</sub>	thermal resistance from junction to solder point		-	-	15	K/W

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	Fig. 5	-	120	-	K/W



### 10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	acteristics					
V <sub>(BR)DSS</sub>	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	50	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	55	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 25 °C; Fig. 12; Fig. 8	1	1.5	2	V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 150 °C; Fig. 12; Fig. 8	0.6	-	-	V
		$I_D$ = 1 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = -55 °C; Fig. 12; Fig. 8	-	-	2.3	V
I <sub>DSS</sub>	drain leakage current	V <sub>DS</sub> = 55 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 150 °C	-	-	500	μA
		V <sub>DS</sub> = 55 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	0.05	10	μΑ
GSS	gate leakage current	V <sub>GS</sub> = 10 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	2	100	nA
		V <sub>GS</sub> = -10 V; V <sub>DS</sub> = 0 V; T <sub>j</sub> = 25 °C	-	2	100	nA
R <sub>DSon</sub> drain-source on-state resistance		V <sub>GS</sub> = 5 V; I <sub>D</sub> = 8 A; T <sub>j</sub> = 150 °C; Fig. 13; Fig. 14	-	-	147	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 8 A; T <sub>j</sub> = 25 °C	-	62	73	mΩ
		V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 8 A; T <sub>j</sub> = 25 °C	-	-	89	mΩ

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		$V_{GS} = 5 \text{ V}; I_D = 8 \text{ A}; T_j = 25 ^{\circ}\text{C}; Fig. 13; Fig. 14}$	-	68	80	mΩ
Dynamic c	haracteristics					
Q <sub>G(tot)</sub>	total gate charge	I <sub>D</sub> = 10 A; V <sub>DS</sub> = 44 V; V <sub>GS</sub> = 5 V;	-	11	-	nC
Q <sub>GS</sub>	gate-source charge	<u>Fig. 11</u>	-	1.6	-	nC
$Q_{GD}$	gate-drain charge	I <sub>D</sub> = 10 A; V <sub>DS</sub> = 44 V; V <sub>GS</sub> = 5 V; Fig. 15	-	4.6	-	nC
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}; Fig. 16$	-	438	584	pF
C <sub>oss</sub>	output capacitance		-	87	104	pF
C <sub>rss</sub>	reverse transfer capacitance		-	62	85	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 5 \text{ V};$	-	8	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 10 \Omega; T_j = 25 ^{\circ}C$	-	118	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	20	-	ns
t <sub>f</sub>	fall time		-	32	-	ns
Source-dra	ain diode		l l			
V <sub>SD</sub>	source-drain voltage	$I_S = 15 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}; Fig. 17$	-	0.85	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s};$	-	33	-	ns
Q <sub>r</sub>	recovered charge	$V_{GS} = -10 \text{ V}; V_{DS} = 30 \text{ V}; T_j = 25 \text{ °C}$	-	60	-	nC

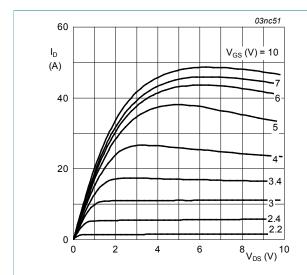


Fig. 6. Output characteristics: drain current as a function of drain-source voltage; typical values  $T_j = 25 ^{\circ} C$ 

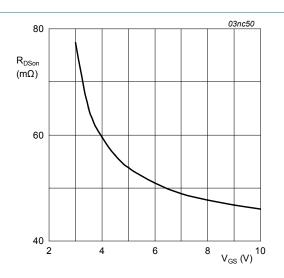
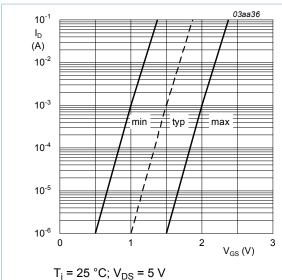


Fig. 7. Drain-source on-state resistance as a function of gate-source voltage; typical values

$$T_j = 25^{\circ}C; I_D = 10A$$



1<sub>j</sub> - 25 C, V<sub>DS</sub> - 5 V

Fig. 8. Sub-threshold drain current as a function of gate-source voltage

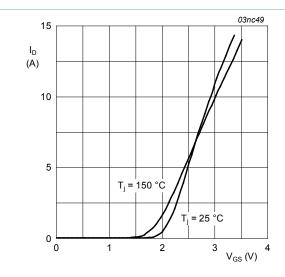


Fig. 10. Transfer characteristics: drain current as a function of gate-source voltage; typical values

$$V_{DS} = 25V$$

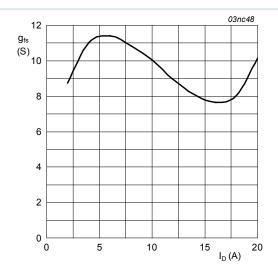


Fig. 9. Forward transconductance as a function of drain current; typical values

$$T_j = 25^{\circ}C; V_{DS} = 25V$$

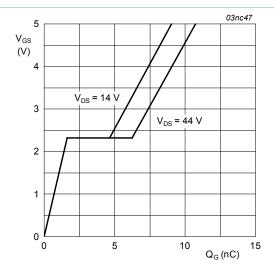


Fig. 11. Gate-source voltage as a function of turn-on gate charge; typical values

$$T_j = 25^{\circ}C; I_D = 10A$$

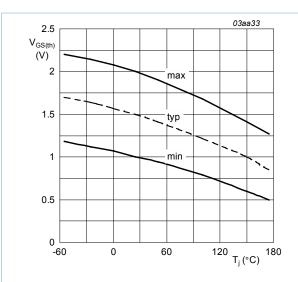


Fig. 12. Gate-source threshold voltage as a function of junction temperature

$$I_D = 1mA; V_{DS} = V_{GS}$$

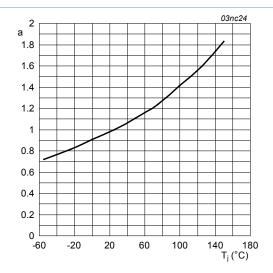


Fig. 14. Normalized drain source on-state resistance factor as a function of junction temperature

$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

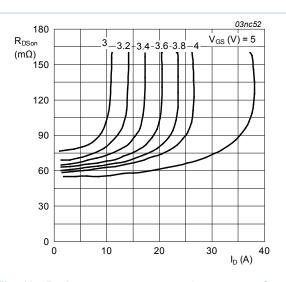


Fig. 13. Drain-source on-state resistance as a function of drain current; typical values

$$T_j = 25^{\circ}C$$

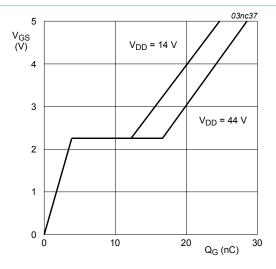


Fig. 15. Gate-source voltage as a function of turn-on gate charge; typical values

$$T_j = 25^{\circ}C; I_D = 15A$$

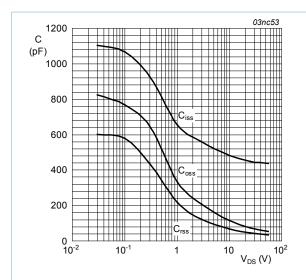
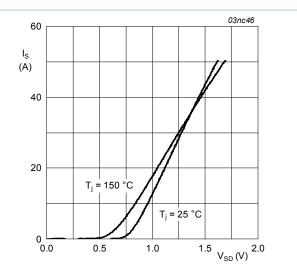


Fig. 16. Input, output and reverse transfer capacitances | Fig. 17. Reverse diode current as a function of reverse as a function of drain-source voltage; typical values

$$V_{GS} = 0V; f = 1MHz$$



diode voltage; typical value

$$V_{GS} = 0V$$

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## 11. Package outline

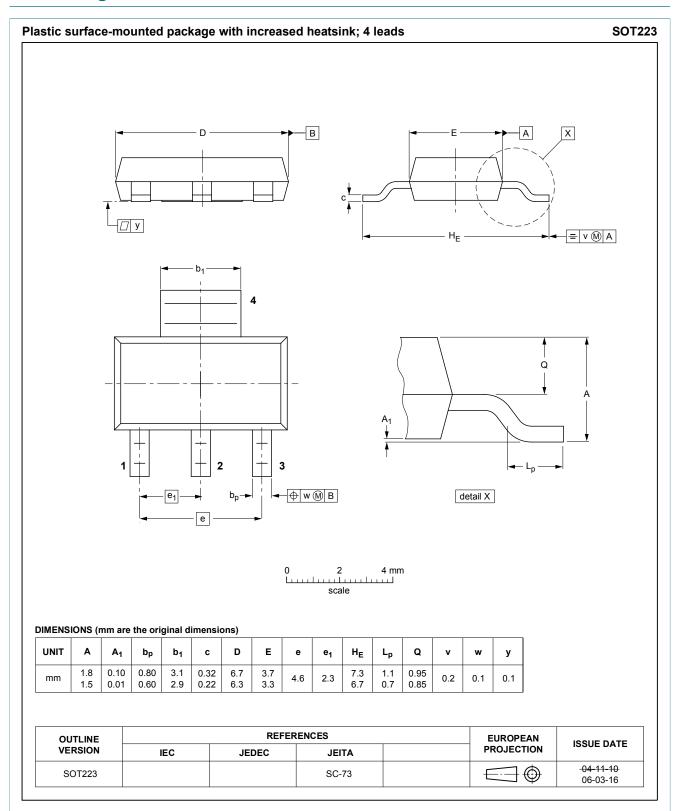


Fig. 18. Package outline SC-73 (SOT223)

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### 12. Legal information

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